


U.S. Department of Commerce, Patent and Trademark Office (PTO Form 1449 modified)		Docket No. AMAT/5730/TCG/ WCVD/LE	Serial No. 10/023,125
INFORMATION DISCLOSURE STATEMENT BY APPLICANT 		Applicant Yoo, et al.	Confirmation No.: 5485
(Use several sheets if necessary)		Filing Date Dec. 17, 2001	Group Unknown
Examiner	Unknown		

U.S. Patent Documents

*Examiner Initial		Document Number	Issue Date	Applicant(s) Name	Class	Subclass	Filing Date If Appropriate
/F.S./	A1	6,482,740	11/19/02	Soininen, et al.	438	686	05/15/01
/F.S./	A2	6,482,733	11/19/02	Raaijmakers, et al.	438	633	04/26/01
/F.S./	A3	6,475,910	11/05/02	Sneh	438	685	09/22/00
/F.S./	A4	6,475,276	11/05/02	Elers, et al.	117	84	10/13/00
/F.S./	A5	6,451,695	09/17/02	Sneh	438	685	12/22/00
/F.S./	A6	6,451,119	09/17/02	Sneh, et al.	118	715	11/29/00
/F.S./	A7	6,447,933	09/10/02	Wang, et al.	428	635	04/30/01
/F.S./	A8	6,423,619	07/23/02	Grant, et al.	438	589	11/30/01
/F.S./	A9	6,420,189	07/16/02	Lopatin	438	2	04/27/01
/F.S./	A10	6,391,785	05/21/02	Satta, et al.	438	704	08/23/00
/F.S./	A11	6,369,430	04/09/02	Adetutu, et al.	257	382	04/02/01
/F.S./	A12	6,368,954	04/09/02	Lopatin, et al.	438	627	07/28/00
/F.S./	A13	6,358,829	03/19/02	Yoon, et al.	438	597	09/16/99

Foreign Patent Documents

*Examiner Initial		Document Number	Date	Country	Class	Subclass	Translation	
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/F.S./	B1	1 033 5264	12/18/98	JP (Abst)	H01L	21/285	<input type="checkbox"/>	<input type="checkbox"/>
/F.S./	B2	0 406 4223	02/28/92	JP (Abst)	H01L	21/285	<input type="checkbox"/>	<input type="checkbox"/>
/F.S./	B3	6 203 3768	02/13/87	JP (Abst)	C23C	16/14	<input type="checkbox"/>	<input type="checkbox"/>

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*Examiner Initial		Including Author, Title, Date, Pertinent Pages, Etc.	
/F.S./	C1	Lee, et al., "Pulsed Nucleation for Ultra-High Aspect Ratio Tungsten Plugfill," Conference Proceedings ULSI XV111 (2002) Materials Research Society	
/F.S./	C2	Sone, et al., "Formation of Low Pressure Chemically Vapour Deposited W Thin Film on Silicon Dioxide for Gate Electrode Application," Thin Solid Films 253 (1994) 377-381	
/F.S./	C3	International Search Report, dated November 25, 2002 for PCT/US02/22486	
Examiner	/Francis Smith/		Date Considered 12/18/2007

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/F.S./	A15 6,355,561	03/12/02	Sandhu, et al.	438	676	11/21/00
/F.S./	A16 6,333,260	12/25/01	Kwon, et al.	438	643	06/24/99
/F.S./	A17 6,305,314	10/23/01	Sneh, et al.	118	723 R	12/17/99
/F.S./	A18 6,287,965	09/11/01	Kang, et al.	438	648	02/23/00
/F.S./	A19 6,284,646	09/04/01	Leem	438	629	08/19/98
/F.S./	A20 6,200,893	03/13/01	Sneh	438	685	03/11/89
/F.S./	A21 6,113,699	09/05/00	Hansen	118	715	11/26/97
/F.S./	A22 6,042,652	03/28/00	Hyun, et al.	118	719	09/07/99
/F.S./	A23 5,994,775	11/30/99	Zhao, et al.	257	751	09/17/97
/F.S./	A24 5,306,666	04/26/94	Izumi	437	192	07/21/93
/F.S./	A25 2002/0162506	11/07/02	Sneh, et al.	118	715	06/28/02
/F.S./	A26 2002/0155722	10/24/02	Satta, et al.	438	704	04/15/02
/F.S./	A27 2002/0121697	09/05/02	Marsh	257	751	04/30/02

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/F.S./	A28	2002/0117399	08/29/02	Chen, et al.	205	125	02/23/01
/F.S./	A29	2002/0109168	08/15/02	Kim, et al.	257	295	01/30/02
/F.S./	A30	2002/0106846	08/08/02	Seutter, et al.	438	200	02/02/01
/F.S./	A31	2002/0105088	08/08/02	Yang, et al.	257	774	10/31/01
/F.S./	A32	2002/0090829	07/11/02	Sandhu, et al.	438	761	01/31/02
/F.S./	A33	2002/0086507	07/04/02	Park, et al.	438	585	12/26/01
/F.S./	A34	2002/0076507	06/20/02	Chiang, et al.	427	569	10/24/01
/F.S./	A35	2002/0061612	05/23/02	Sandhu, et al.	438	151	01/14/02
/F.S./	A36	2002/0055235	05/09/02	Agarwal, et al.	438	430	10/29/01
/F.S./	A37	2002/0048880	04/25/02	Lee	438	253	08/08/01
/F.S./	A38	2002/0031618	03/14/02	Sherman	427	569	10/09/01
/F.S./	A39	2002/0037630	03/28/02	Agarwal, et al.	438	430	10/29/01
/F.S./	A40	2002/0019121	02/14/02	Pyo	438	618	06/20/01

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/F.S./	A41	2002/0004293	01/10/02	Soininen, et al.	438	584	05/15/01
/F.S./	A42	2001/0054769	12/27/01	Raaijmakers, et al.	257	758	04/26/01
/F.S./	A43	2001/0029094	10/11/01	Mee-Young, et al.	438	597	09/16/99
/F.S./	A44	2001/0024387	09/27/01	Raaijmakers, et al.	365	200	02/22/01
/F.S./	A45	2001/0002280	05/31/01	Sneh	427	255.28	12/22/00
/F.S./	A46	2001/0009695	07/26/01	Saanila, et al.	427	255.39	01/18/01

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